

[54] NO₂ THIN FILM ELECTRO-OPTIC SWITCH

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[52] U.S. Cl. 350/96.14; 350/356

[58] Field of Search 350/353, 355, 356, 96.12, 350/96.13, 96.14, 96.34, 354, 386

[56] References Cited

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[57] ABSTRACT

An electro-optic device includes a niobium dioxide (NbO₂) crystalline material, a light source for illuminating the crystalline material and means for applying an electrical field, which can be varied, to the crystalline material, so that the intensity of the light (or electromagnetic energy) passing through the crystalline material will be a function of the electrical field. A reactive ion-beam sputtering technique for fabricating NbO₂ crystalline thin films suitable for use in these electro-optic devices is also disclosed.

4 Claims, 10 Drawing Figures

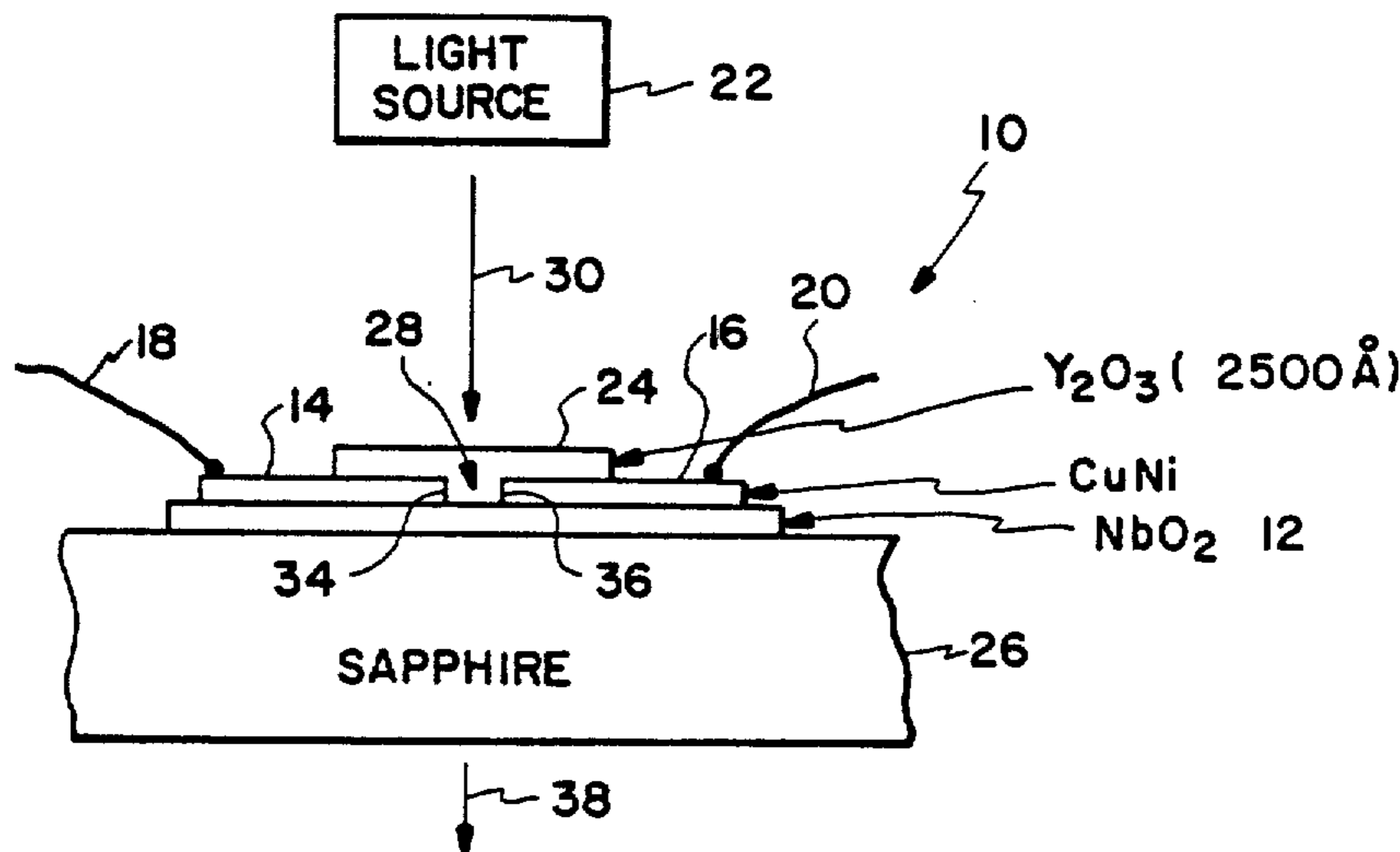


Fig. 1

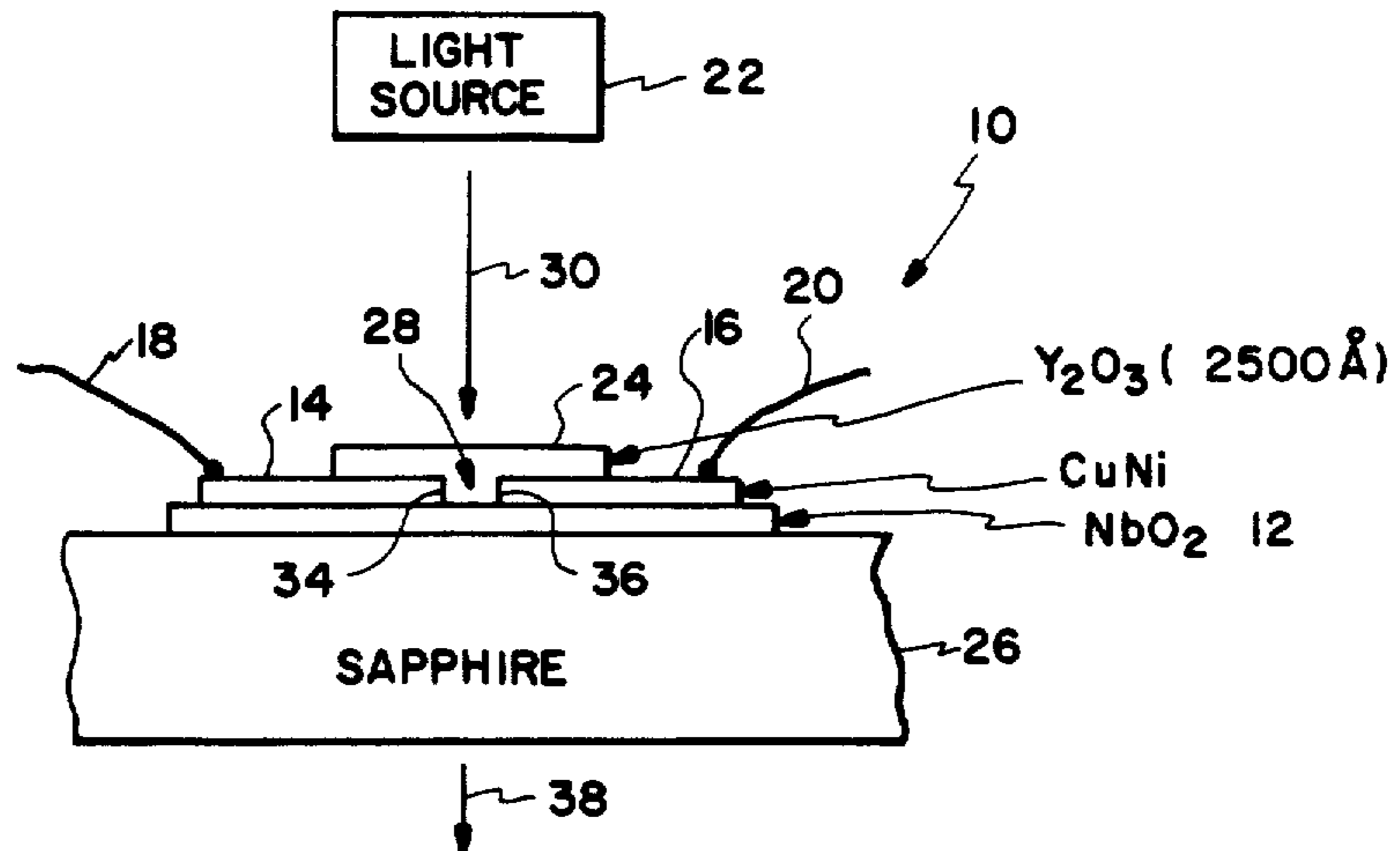


Fig. 3

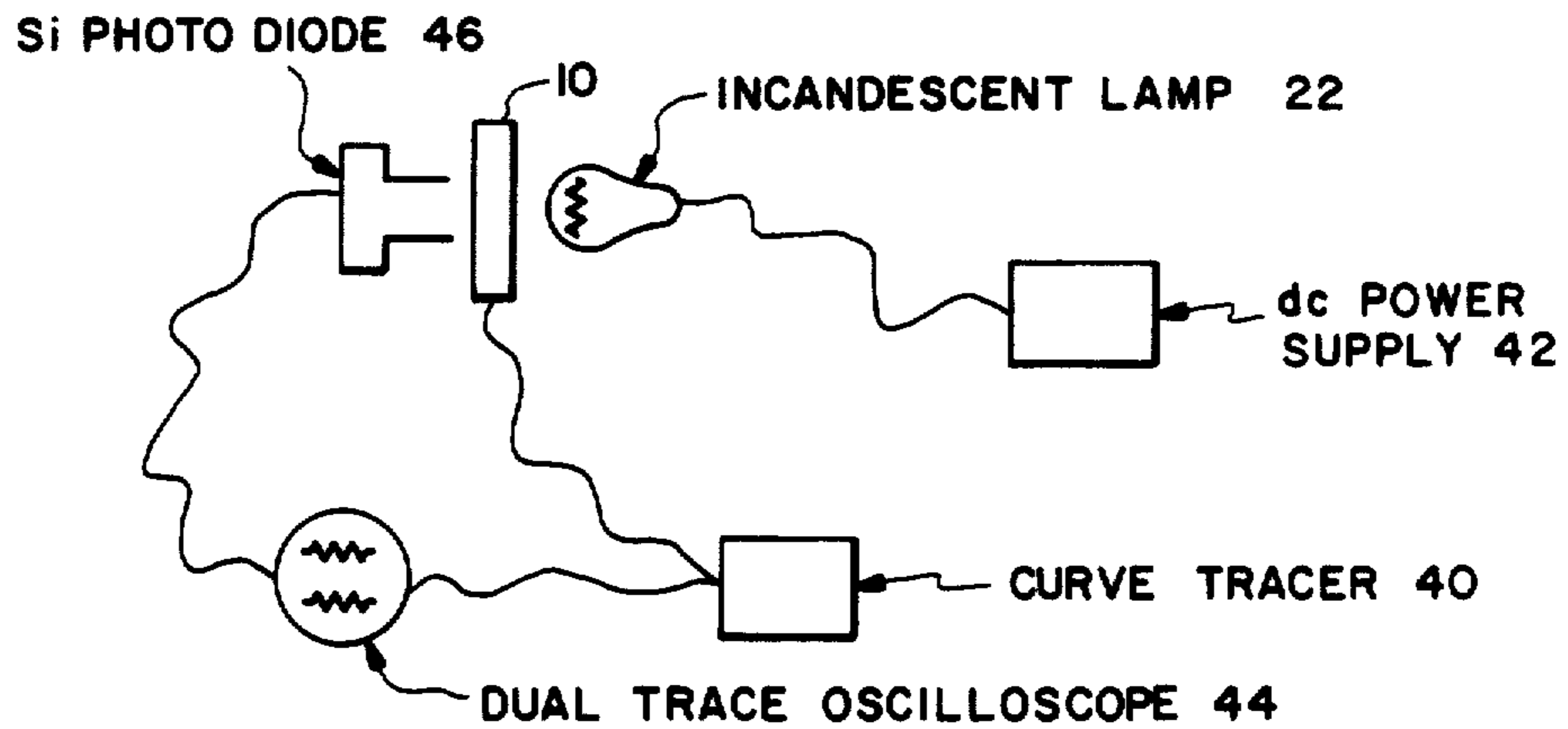


Fig. 9

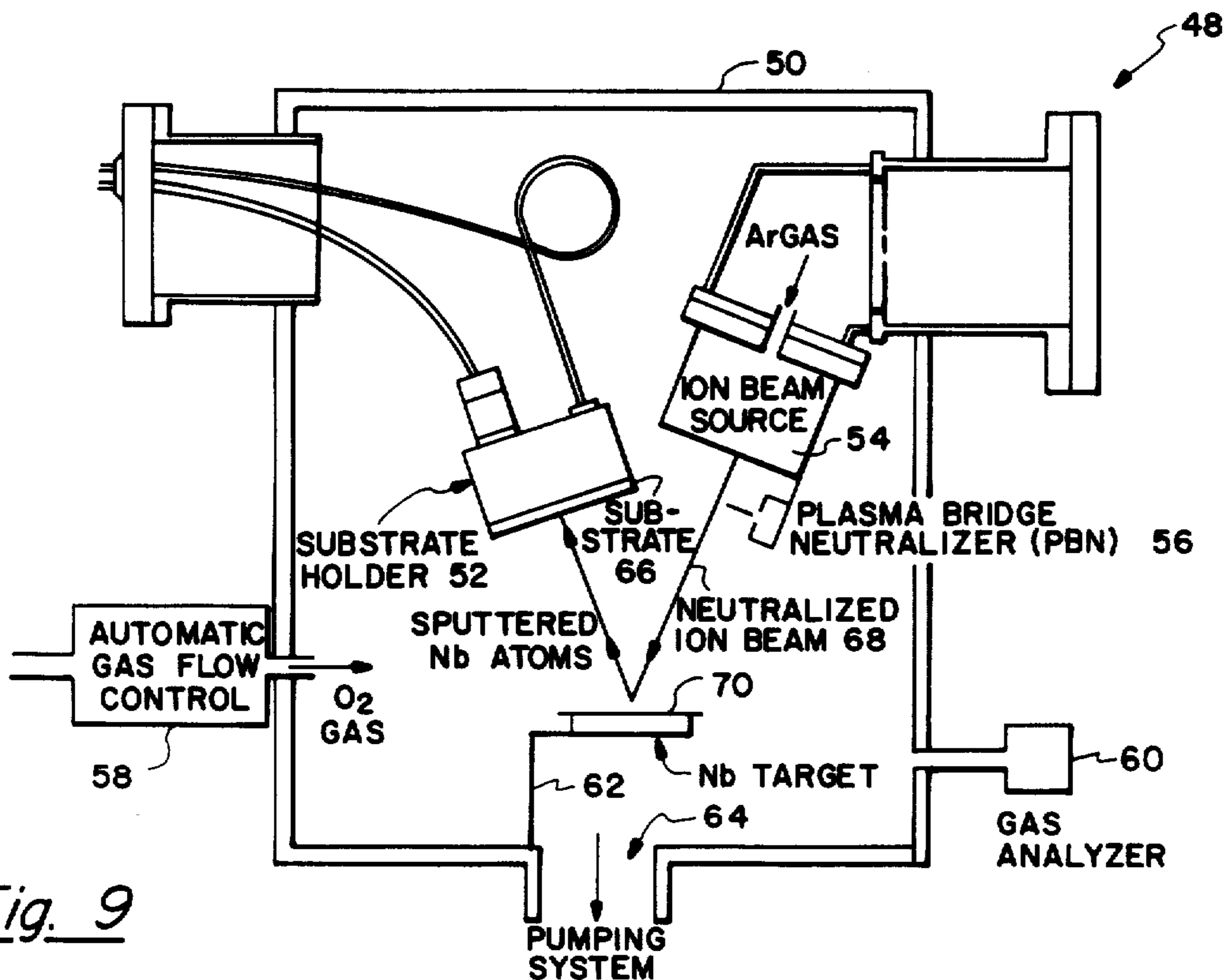


Fig. 2
CURRENT
(20mA / VERTICAL
DIVISION)

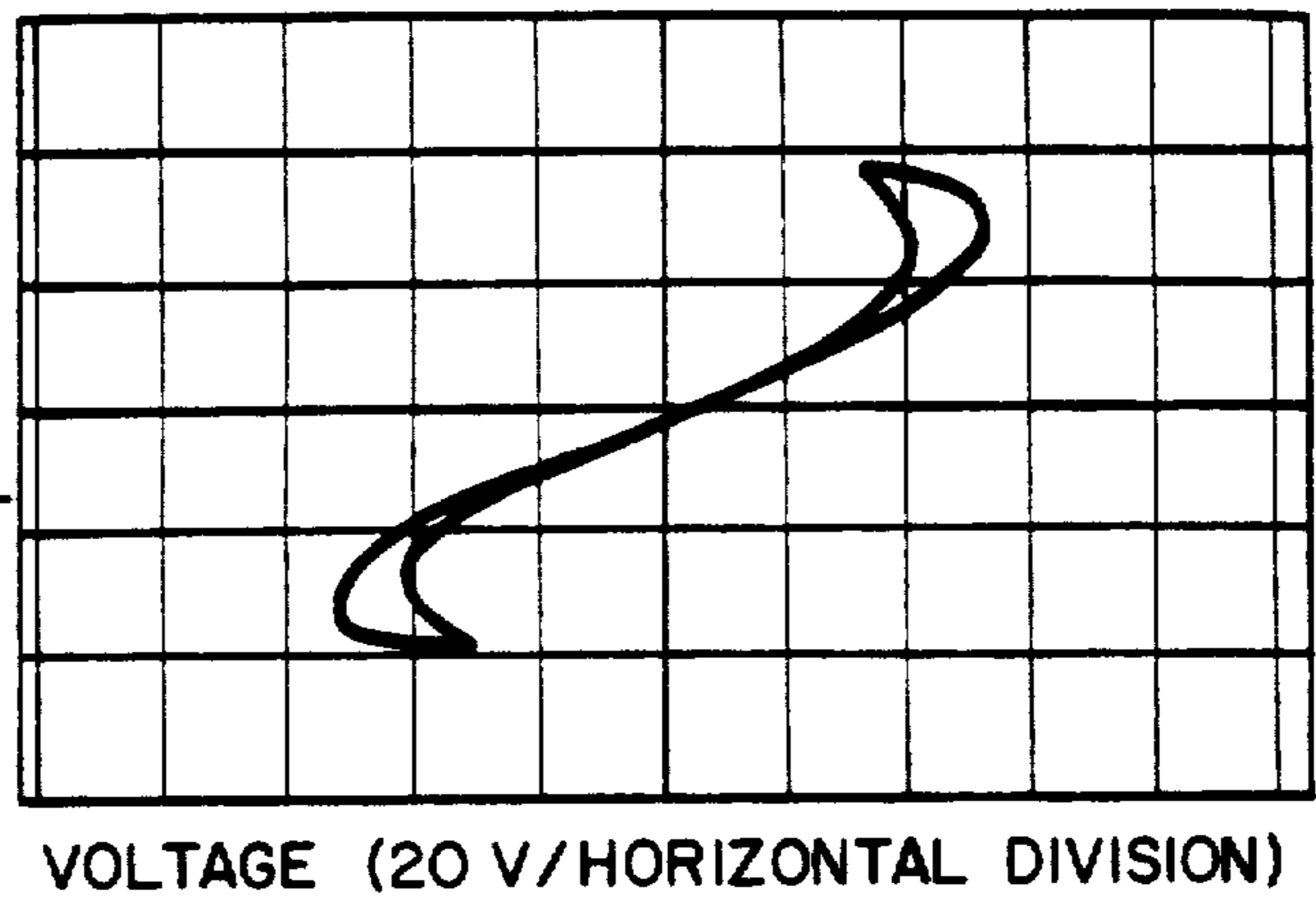


Fig. 4

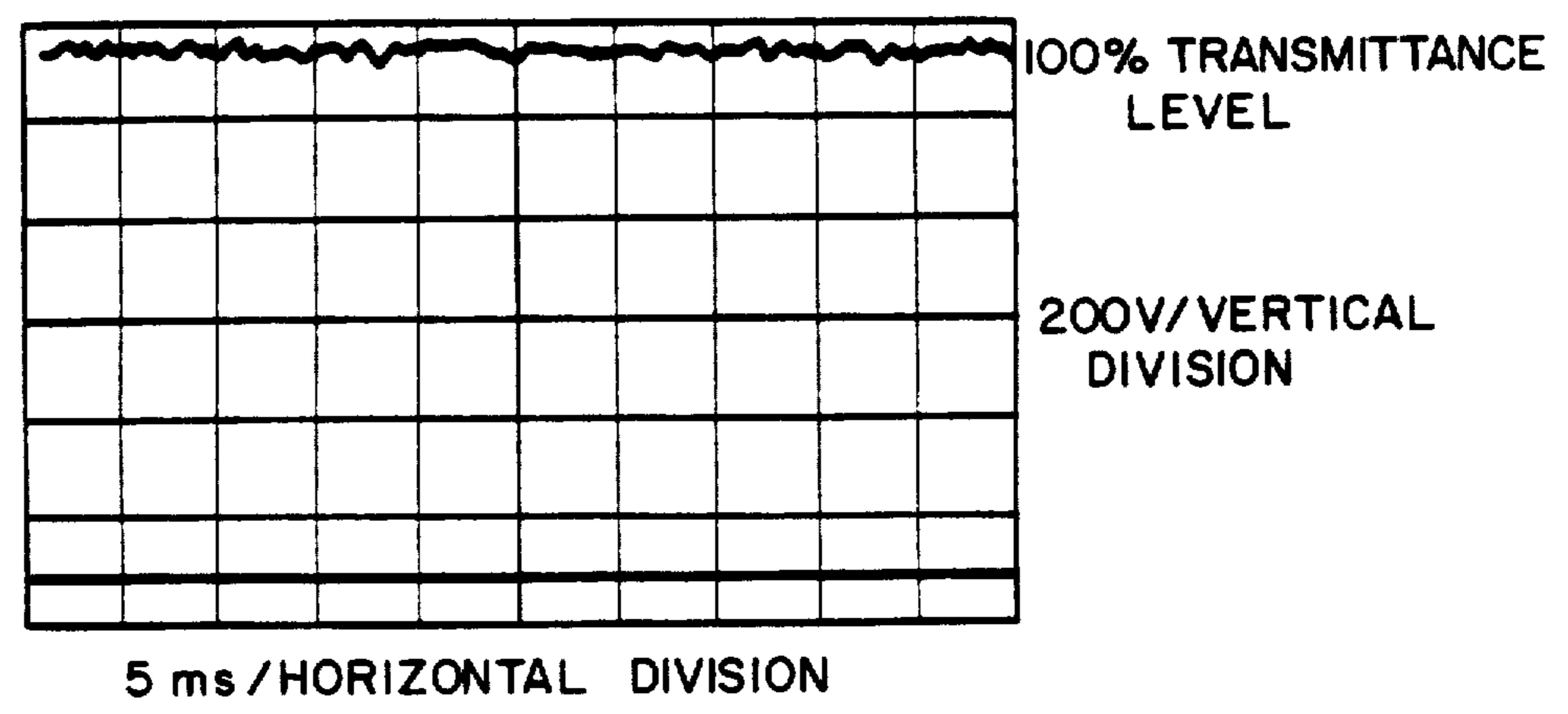


Fig. 5

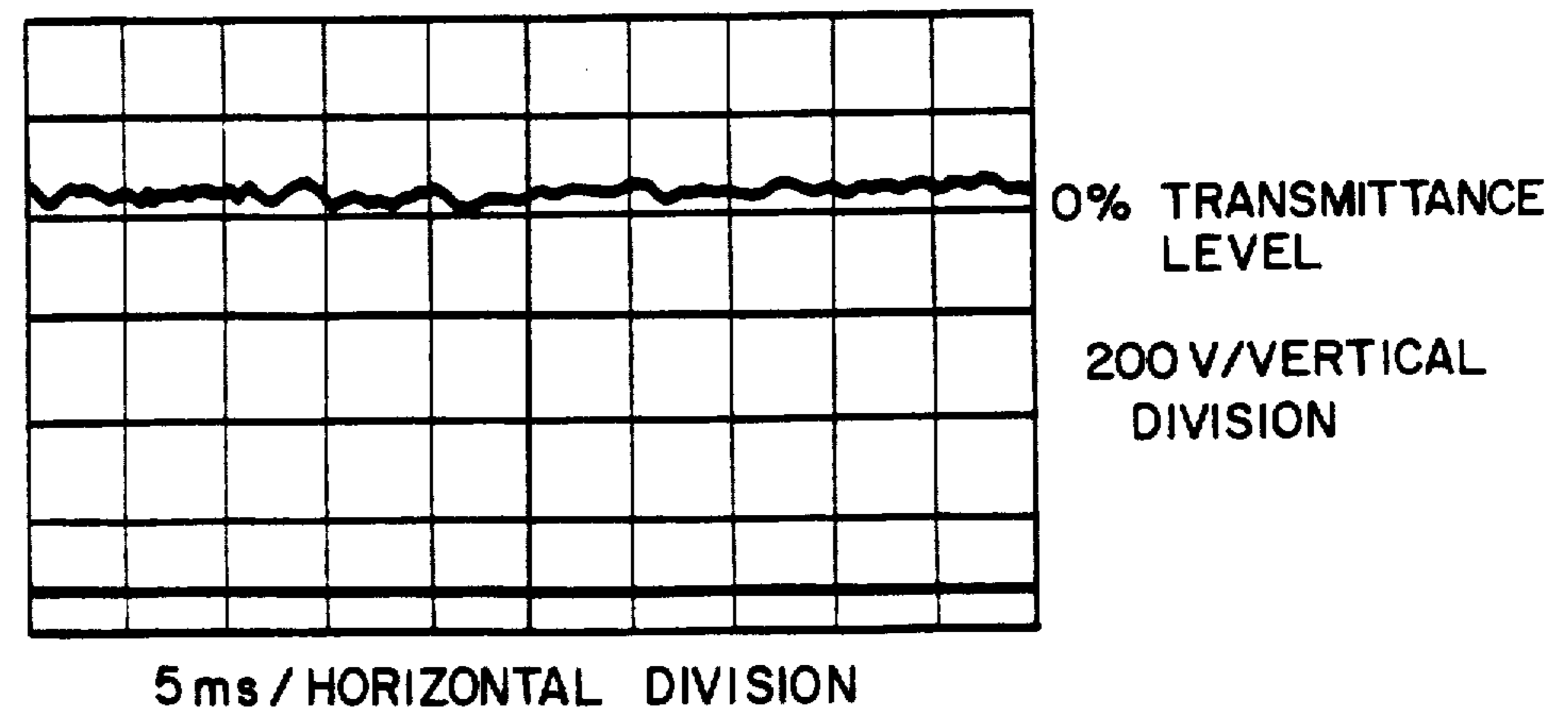


Fig. 6

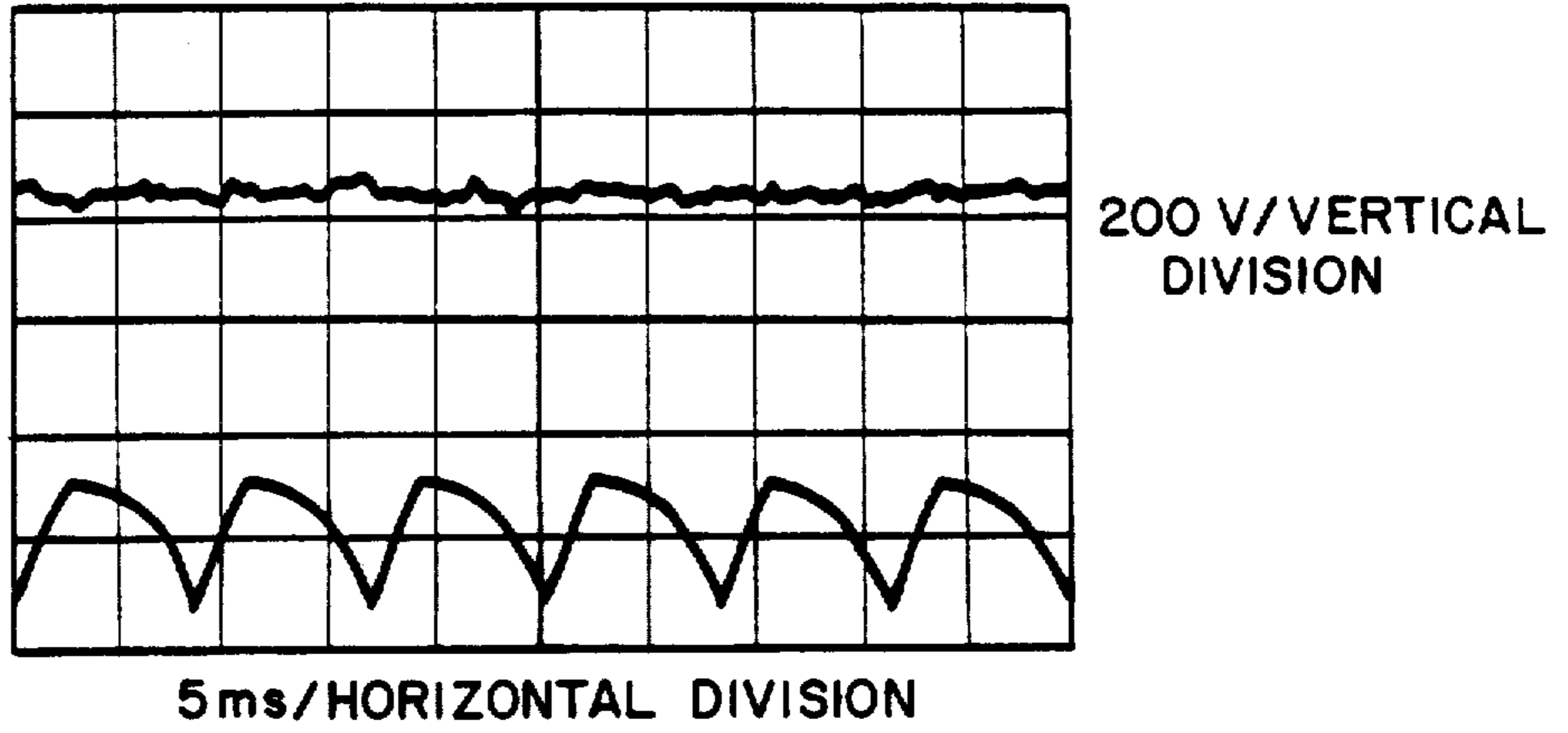


Fig. 7

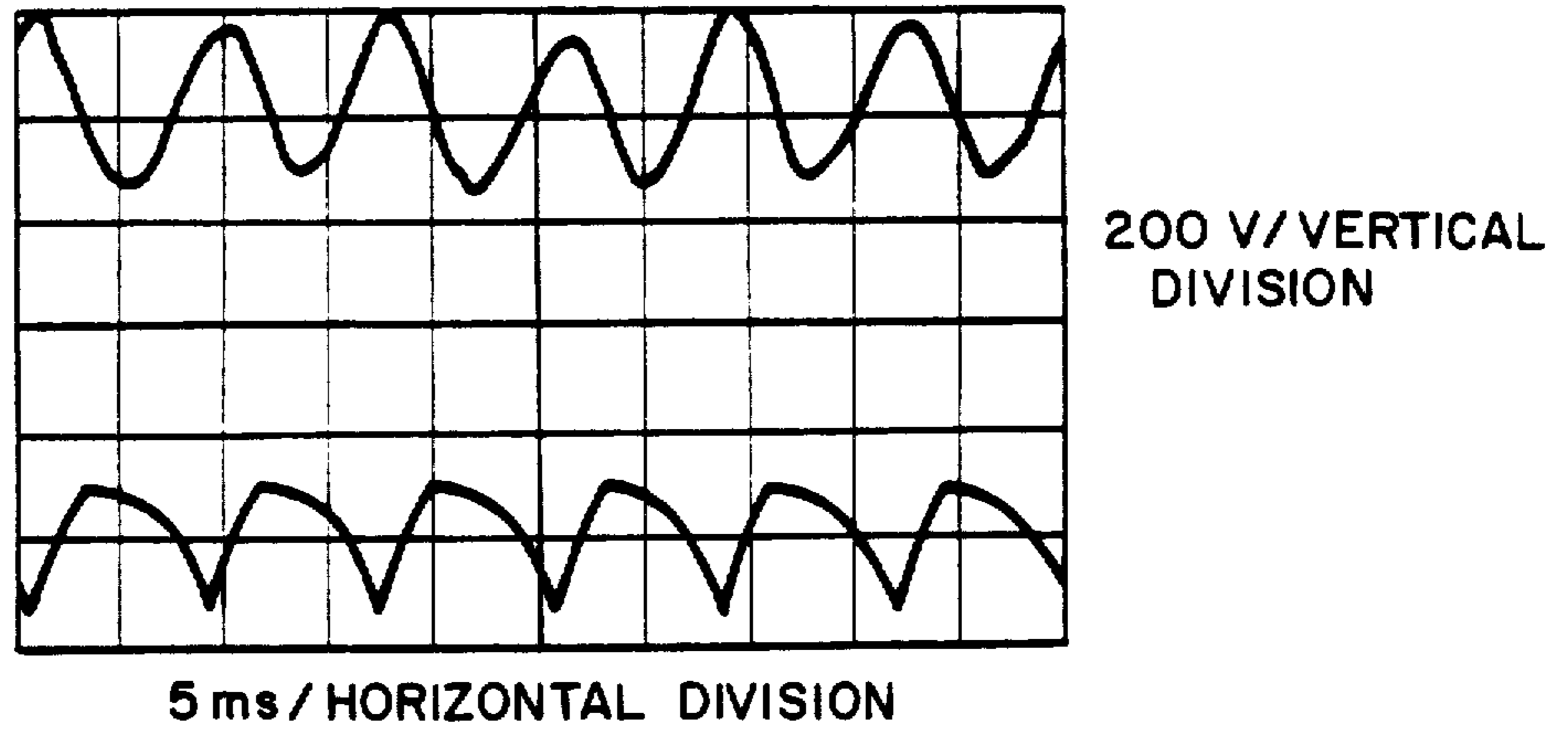
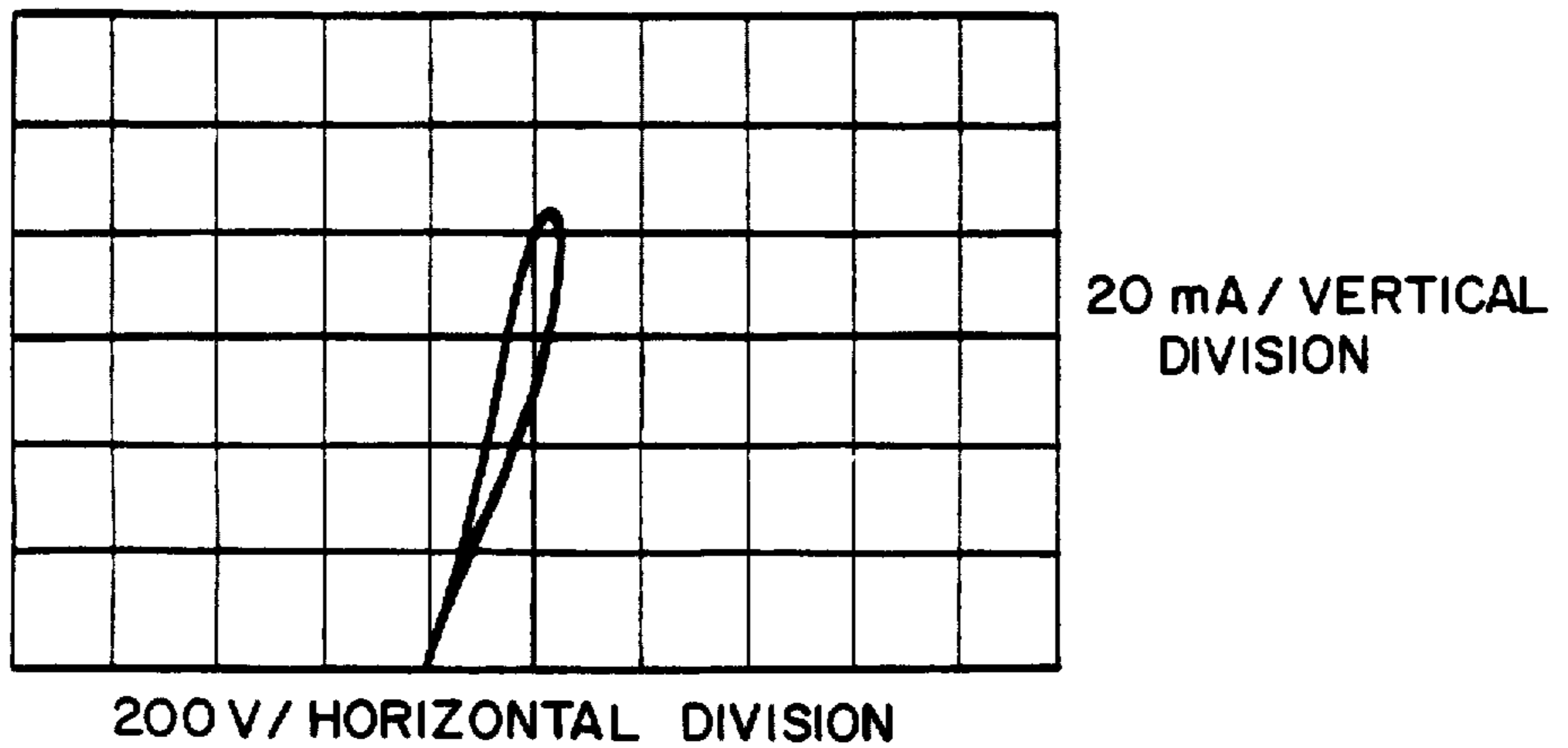


Fig. 8



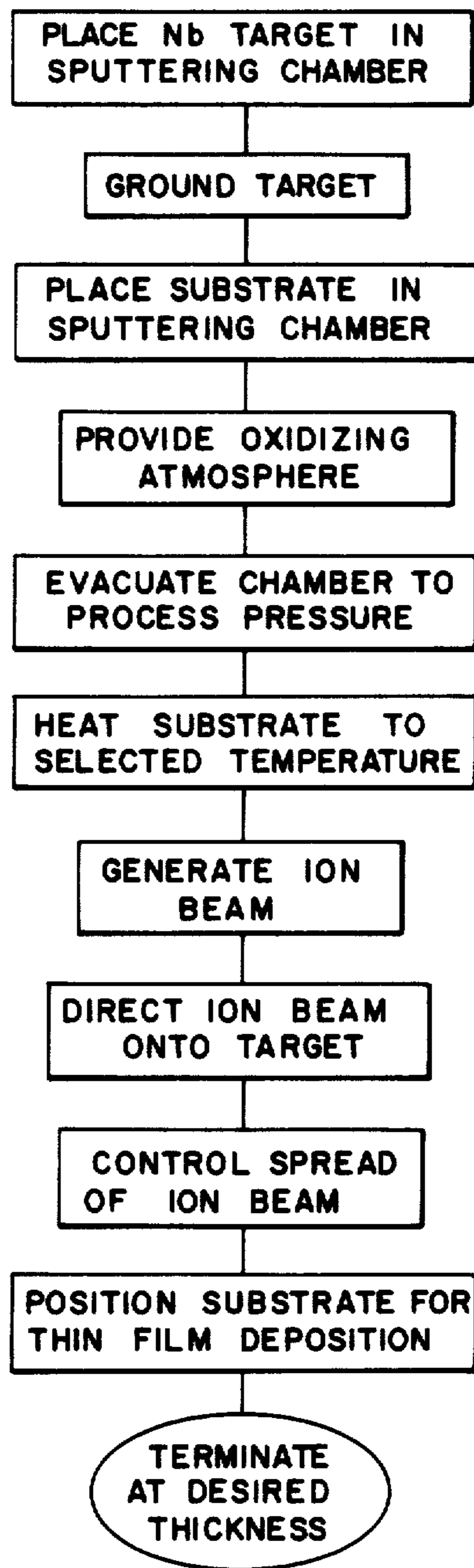


Fig. 10

NO₂ THIN FILM ELECTRO-OPTIC SWITCH

The United States Government has rights in this invention pursuant to Contract No. DAAK70-83-C-0017, awarded by the army.

BACKGROUND OF THE INVENTION

1. FIELD OF THE INVENTION

This invention relates to means of electrically stimulating optical modulation switching in NbO₂ crystalline thin films and methods of fabricating such devices.

2. RELATED ART

Electrical switching in NbO₂ has been observed, particularly in the context of transient noise suppression applications. NbO₂ threshold switch devices capable of suppressing kilo volt - level pulses with nanosecond widths have been fabricated. On-to-off resistance ratios of nearly three orders of magnitude are reported. An electrically driven reversible semiconductor to-metal phase transition is theorized as the basis for the electrical switching phenomena observed in NbO₂.

The electro-optic switching properties of NbO₂ however, have not heretofore been disclosed.

SUMMARY OF THE INVENTION

An electro-optic device includes a niobium dioxide (NbO₂) crystalline material, a light source for illuminating the crystalline material and means for applying an electric field, which can be varied, to the crystalline material, so that the intensity of the light (or electromagnetic energy) passing through the crystalline material will be a function of the applied electric field.

A reactive ion beam sputtering technique for fabricating NbO₂ crystalline thin films suitable for use in these electro-optic devices is also disclosed.

BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is an electro-optic NbO₂ crystalline thin film device in accordance with the present invention.

FIG. 2 displays the current voltage characteristics of a circuit including a NbO₂ thin film as an electro-optic active element.

FIG. 3 is a test setup for the electro-optic behavior of the device of FIG. 1.

FIG. 4 displays the temporal response of the device of FIG. 1 using the setup of FIG. 4 with the lamp on and drive off.

FIG. 5 displays the temporal response of the device of FIG. 1 in the setup of FIG. 4 with the lamp off and drive off.

FIG. 6 displays the temporal response of the device of FIG. 1 in the setup of FIG. 4 with the lamp off and the drive on.

FIG. 7 displays the temporal response of the device of FIG. 1 in the setup of FIG. 4 with the lamp on and the drive on.

FIG. 8 displays the current-voltage characteristics of the NbO₂ thin film employed in FIGS. 4-7.

DESCRIPTION OF THE PREFERRED EMBODIMENT

Electro-optic NbO₂ device 10 of FIG. 1 includes an NbO₂ crystalline layer 12, means for applying an electric field to a portion of layer 12 (e.g., CuNi electrodes 14 and 16, and wires 18 and 20 connected to a power supply which is not shown), and an electromagnetic energy source (such as light source 22). It is preferable

to further include a transparent passivation layer (such as Y₂O₃ layer 24) with layer 12 formed on a transparent substrate (such as sapphire 26). Electrodes 14 and 16 are spaced to provide an aperture 28 therebetween.

When layer or material is referred to herein as "transparent", it means that the material will transmit with no substantial attenuation at least that portion of the electromagnetic spectrum of interest in a particular application.

In operation, source 22 illuminates aperture 28 with light beam 30. An electric field is generated between ends 34 and 36 of electrodes 14 and 16, respectively. In device 10 some of the field lines will curve through 180 degrees as they pass through layer 12. This curvature of field lines was employed in generating the data disclosed herein to insure that if anisotropic effects were associated with the observed electro-optic behavior, all directions in the NbO₂ layer were subjected to an electric field. The general electro-optic behavior herein disclosed will occur for any E field direction in crystalline layer 12, although some directions may enhance the effect.

With no electric field, the transmission of light through layer 12 (and transparent layer 24 and substrate 36) is basically unaffected resulting in an output beam 38 of a given intensity. As the strength of the electric field is increased, the transmission of light is increasingly attenuated until transmittance is virtually zero.

FIG. 2 shows the electrical switching behavior for device 10 with an aperture 28 of 0.1 millimeters by 1 millimeter. The current through layer 12 is shown as a function of the applied voltage. The looping in the trace is an instrumental artifact, due to uncompensated reactive pickup, and not device hysteresis. Nonlinear electrical switching behavior is clearly exhibited. The tips of the trace which turn inward indicate negative resistance regions.

The electro-optic behavior of the present invention is demonstrated by the testing setup of FIG. 3 which includes device 10. Device 10 in this case had an aperture 28 which was 1 millimeter square. The electric field was supplied by a curve tracer 40 (a Tektronix 577 tracer was actually used). An incandescent lamp was used as electromagnetic source 22 in conjunction with a dc power supply 42. The data in FIGS. 4-7 was recorded using a dual trace oscilloscope 44. The intensity of output beam 38 was monitored with a Si photodiode 46. Layer 12 was a stoichiometric NbO₂ thin film about 0.5 microns thick. FIGS. 4-7 show the photodiode 46 voltage signal and the drive voltage signal applied to electrodes 14 and 16 versus time.

FIG. 4 shows where the 100 percent transmittance level (i.e., lamp on) was established with the E field being zero. FIG. 5 shows where the zero percent transmittance level (i.e., the lamp off) was established with the E field being zero. FIG. 6 shows the drive voltage with the light source 22 off. Note that the drive voltage has no effect on the zero transmittance level. Further the rectified sine wave drive voltage is distorted due to the nonlinear load. FIG. 7 shows the temporal modulation response with the drive 40 and light source 22 on.

FIG. 7 clearly demonstrates that optical modulation/switching accompanies the electrical switching phenomenon observed for NbO₂.

FIG. 8 shows the current-voltage characteristics for device 10 used to generate the data in FIGS. 4-7.

FIG. 9 is a schematic of a reactive ion-beam sputtering apparatus 48 used to make device 10. When used

herein "crystalline" means a material which exhibits long range order compared to the crystal lattice parameter. Apparatus 48 includes a hermetic chamber 50, substrate holder 52, ion-beam source 54, means for controlling the spread of the ion-beam (such as plasma bridge neutralizer 56), automatic gas flow control 58, gas analyzer 60, and target holder 62. An orifice 64 leads to a pumping system (not shown). Target holder 62 grounds the target (i.e., places it at a negative potential with respect to the ions).

In operation, an oxidizing atmosphere is provided within chamber 50. good oxidizing atmosphere is O₂ mixed with Ar gas from the ion-beam source. The chamber is then evacuated to a pressure sufficient to allow sputtering of the NbO₂ thin film. Substrate 66 is heated to a temperature sufficient to allow an NbO₂ crystalline thin film to form on substrate 66.

Ion-beam 68 is generated by source 54. Typically Ar ions are employed. The ion beam is directed onto the Nb target 72 to sputter Nb atoms from it. Substrate 66 is positioned so that a majority of the sputtered Nb atoms strike substrate 66.

It is important to control the spread of ionbeam 68 in order to insure good quality NbO₂ crystalline thin films. Despite the fact that the target is a metal, beam spreading is a problem because the oxidizing atmosphere allows an oxide insulating layer to form on target 70. This in turn reduces the attractive force between the target and the ions in beam 68 which exacerbates beam spreading. Beam spreading can be effectively controlled by, for example, neutralizing ion-beam 68 by injecting sufficient electrons into beam 68 to balance the positive charge. Plasma bridge neutralizer 56 was employed for this purpose.

The following parameters yielded NbO₂ crystalline thin films of about 0.5 microns on a sapphire substrate:

Parameter	Value
Ion-beam voltage	1.2 kV
Beam current (neutralized)	50 mA
Beam current density at target	~1 mA/cm ²
O ₂ and Ar background pressure	Low to mid 10 ⁻⁴ T
O ₂ /Ar flow rate	0.08 to 0.09

-continued

Deposition rate	1 Å/sec
Temperature	600° C.
Target - substrate Distance	15 cm

A temperature of 600° C. was essentially the lowest temperature at which apparatus 48 operating with the above parameters could produce acceptable NbO₂ crystalline thin films. The lowest temperature sufficient for formation of crystalline thin films is preferable because the additional energy associated with higher temperatures can cause inhomogenous thin films.

Standard photolithographic techniques were used for fabrication of the remainder of device 10, with ion milling used to pattern the NbO₂ films.

What is claimed is:

1. An electro-optic device, comprising: a niobium dioxide (NbO₂) crystalline material; means for illuminating at least a portion of said crystalline material with electromagnetic energy, wherein said electromagnetic energy includes wavelengths which are at least partially transmitted through said crystalline material, and wherein said electromagnetic energy enters said crystalline material at a first location and exits said crystalline material at a second location; means for applying an electric field to said crystalline material, wherein the direction of said electric field is coextensive with at least a portion of the path of said electromagnetic energy between said first and second locations; and means for varying said electric field, so that the intensity of said electromagnetic energy at said second location will be a function of said electric field.
2. The device of claim 1 wherein said crystalline material is a layer less than one micron thick.
3. The device of claim 2 further including a sapphire substrate and wherein said crystalline material is formed on the surface of said substrate.
4. The device of claim 1 wherein said means for applying an electric field includes first and second opaque electrodes, said first and second opaque electrodes being spaced apart and in contact with said crystalline material, the space between said electrodes forming an aperture which is illuminated by said illumination means.

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UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 4,712,857

DATED : December 15, 1987

INVENTOR(S) : JAMES C. LEE

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Item 54, in the title, delete "NO₂ THIN FILM ELECTRO-OPTIC SWITCH" and substitute with --NbO₂ THIN FILM ELECTRO-OPTIC SWITCH--.

**Signed and Sealed this
Seventh Day of June, 1988**

Attest:

DONALD J. QUIGG

Attesting Officer

Commissioner of Patents and Trademarks